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Dr. Colleen Frazer joins Covalent Metrology to lead XRD / XRR Services

January 11th, 2018 Santa Clara, CA – Covalent Metrology announced today that Dr. Colleen Frazer has joined the company as Director of X-ray Diffractometry (XRD) and X-ray Reflectometry (XRR) Services. Dr. Frazer comes to Covalent with 20 years experience working as an XRD / XRR specialist at several world class institutions. The breadth and depth of her knowledge in instruments, applications, software and data analysis significantly elevates Covalent Metrology's XRD and XRR services, and positions the company to generate and deliver outstanding data and insights to its clients.

Before working for Covalent Metrology, Dr. Frazer was an XRD/XRR Senior Scientist at EAG Laboratories focused particularly on high resolution applications. She previously spent nine years with Philips Lumileds as a characterization expert focused on XRD and three years before that as a post-doctoral fellow at Sandia National Laboratories. She obtained her PhD in Materials Science and Engineering from the University of Kentucky, concentrating on XRD residual stress measurements in highly textured materials.

"We are very proud to welcome Colleen to our team," Covalent Metrology's CEO Craig Hunter declared. "Her skill, leadership and professionalism will be an enormous asset as we build out our XRD and XRR capabilities. These are powerful analytical instruments that are used extensively in multiple industries pursuing cutting edge materials science innovation. But it is absolutely critical to have someone deeply skilled in these techniques responsible for tool set-up and operation as well as modeling and interpreting results."

Dr. Frazer remarked, "I am very excited to join Covalent Metrology and to lead their efforts in this area. Its great to see a new player in the field bringing fresh thinking about the metrology and characterization service business; I wholeheartedly endorse Covalent's vision to reduce the cost and time to high quality data in order to empower customers to make better R&D decisions."

Over the past year, Covalent Metrology has introduced multiple new analytical services including scanning probe miscroscopy (SPM), spectral ellipsometry and UV-Vis-NIR spectrophotometry, optical profilometry and now XRD and XRR. Its operating model and business strategy enable low cost and rapid turnaround. Their Metrology Partners unit offers a suite of services based on client-specific development objectives aimed at improving in-house and external metrology quality, speed and cost. Headquarters are located in Santa Clara, CA.

For more information call (408) 498-4611 or visit the Company's website at http://www.covalentmetrology.com.